## A com parison between several correlated stochastic volatility m odels

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## A bstract

We compare the most common SV models such as the Omstein-Uhlenbeck (OU), the Heston and the exponential OU (expOU) models. We try to decide which is the most appropriate one by studying their volatility autocorrelation and leverage e ect, and thus outline the limitations of each model. We add empirical research on market indices con ming the universality of the leverage and volatility correlations.

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Them ultiplicative di usion process is considered to be them ost popularm odel in nance. We thus have that the log-price change without average describes the di usive process X-(t) =  $_1$  (t) (in the Itô sense), where is the volatility (assumed to be constant) and  $_1$  is B rownian noise with h  $_1$  (t)  $_1$  (t) i =  $_1$  (t). However, this model is unable to capture most of the statistical properties of real markets, those called stylized facts.

The stochastic volatility (SV) models are a natural way out to avoid the inconsistencies of the log-B rownian model by still assuming that X follows a diusion process but now with a random . However, the dynamics of has not been de nitively attached to any specic SV model. In this sense, we want to discern between the most common SV models. Among others we have:

(a) The Omstein-Uhlenbeck (OU) SV model [1,2]

\_(t) = ( m) + k 
$$_2$$
 (t); (t) = m + k e  $_2$  (t)  $_2$  (t)  $_2$  (t)  $_2$  (t)  $_2$  (t)

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(b) The Heston SV model [3,4] (with V <sup>2</sup>)

$$V_{-}(t) = (V m^{2}) + k^{\frac{p}{V}} v_{2}(t);$$
 (2)

(c) And, nally, the exponential O mstein-Uhlenbeck (expOU) SV model [5] (w ith Y  $\ln (=m)$ 

$$Y_{-}(t) = Y + \frac{k}{m} {}_{2}(t); \quad Y(t) = m + \frac{k}{m} {}_{1}^{Z^{t}} e^{-(t-t^{0})} {}_{2}(t^{0})dt^{0};$$
 (4)

Note that the Heston model does not provide a closed equation for the volatility. This can be a serious drawback in case we want to deal with analytical expressions. In addition, we suppose that noises are correlated (i.e.,  $h_1$  (t)  $_2$  (t<sup>0</sup>) i =1). This allows us to explain some stylized facts.

The leverage e ect [6] is measured by: L() hdX  $(t+)^2$ dX (t)i=hdX  $(t)^2i$ . For the models above we have

$$L_{OU}() = 2 \frac{p_{\frac{1}{2}(1+2e)}^{\#}}{(1+2)^{2}m} e ; L_{H}() 4_{\frac{1}{k}}e ; (5)$$

$$L_{expOU}() = \frac{2 k}{m^2} e^{2} = 2 exp 2^2 e$$
 ; (6)

> 0 and L() = 0 for negative . It seems impossible to derive an analytical expression for the Heston leverage because V (t) does not have a closed expression (cf.Eq. (3)). The leverage given in Eq. (5) is exact only when  $m^2 = k^2 = 2$  but Ref. [4] shows that this is not true for the D ow Jones. We will have thus to simulate the process to compute the leverage e ect in each specic Heston case. Eqs. (5) { (6) are plotted and compared with data in Fig. 1. The data is too noisy to assert which is the most appropriate model. In any case, the three models have the desired exponential decay with a characteristic time of the order of few days. We also note that, without the correlation coe cient , there is no leverage and data con  $\,\mathrm{rm}\,\mathrm{s}\,\mathrm{that}\,<\,0\,$  [7].

The volatility autocorrelation is C ( ) IndX (t)  $^2dX$  (t+ ) $^2i$  IndX (t)  $^2ihdX$  (t+ )2i=Var[dX (t)2]. In this case, we can exactly derive this correlation for each m odel.W e have

$$C_{OU}() = \frac{{}^{2}e ({}^{2}e + 1)}{4^{2}(2 + {}^{2}) + 1}; \quad C_{H}() = {}^{2}e ;$$
 (7)

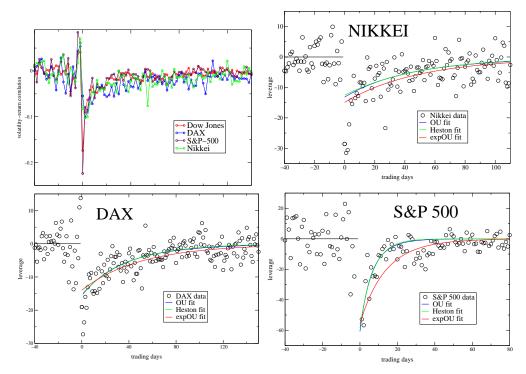


Fig. 1. The leverage e ect for several daily price indices. We also add the leverage function L() t for the dierent SV models. The S&P 500 is much more liquid.

$$C_{\exp OU}() = \frac{\exp(4^{-2}e^{-}) - 1}{3\exp(4^{-2}) - 1}$$
: (8)

The volatility autocorrelation observed in empirical data shows at least two di erent time scales (see Fig. 2 and Ref. [8]). The shortest one coincides with the leverage correlation time while the second scale is of the order of years, around 10 times bigger than the leverage time. The OU and Heston models are not capable of reproducing the slowest time decay but the expOU model has a nontrivial decay with the two time scales:

$$C_{expOU}()$$
 e ( > 1);  $C_{expOU}()$  e  $(k=m)^2$  ( < 1); (9)

where the faster decay is given by the di usive coe cient k=m and the slow decay of the volatility is provided by the reversion coe cient (cf. Eq. (4)).

Therefore, we conclude that the exp0U m odel appears to be as m ore realistic. Further investigations on this model are required to con rm this assertion. However, an alternative choice is to sophisticate the OU and Heston models. A second time scale can be generated by including a third SDE for m. In a previous work [8], we have studied this possibility for the OU model with some success by taking:  $\underline{m}$  (t) =  $\underline{m}$  (m ) +  $\underline{k}$  +  $\underline{k}$  +  $\underline{k}$  3 (t). A similar analysis can be performed for the Heston model.

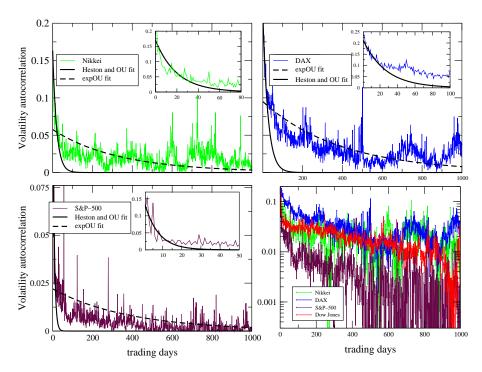


Fig. 2. The volatility correlation for several daily indices. We add two exponential tsone with a short range (similar to the leverage time scale) and a second one for the larger time lags.

## A cknow ledgem ents

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